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(54) **METHOD FOR ANALYZING GENES OF INDUSTRIAL YEASTS**

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(57) **ABSTRACT**

An object of the present invention is to provide a method for analyzing gene of an industrial yeast. The method of the present invention comprises

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- (a) determining the whole genome sequence of the industrial yeast; and
- (c-1) selecting a gene of the industrial yeast encoding an amino acid sequence having 70 to 97% identity to an amino acid sequence encoded by the gene of *Saccharomyces cerevisiae*, or
- (c-2) selecting a gene of the industrial yeast consisting of a nucleotide sequence having 60 to 94% identity to the nucleotide sequence of the gene of *Saccharomyces cerevisiae*.

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